



Welcome to [E-XFL.COM](https://www.e-xfl.com)

### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	2400
Number of Logic Elements/Cells	10800
Total RAM Bits	81920
Number of I/O	404
Number of Gates	468252
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	560-LBGA Exposed Pad, Metal
Supplier Device Package	560-MBGA (42.5x42.5)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xcv400-5bg560c">https://www.e-xfl.com/product-detail/xilinx/xcv400-5bg560c</a>

## Virtex Architecture

Virtex devices feature a flexible, regular architecture that comprises an array of configurable logic blocks (CLBs) surrounded by programmable input/output blocks (IOBs), all interconnected by a rich hierarchy of fast, versatile routing resources. The abundance of routing resources permits the Virtex family to accommodate even the largest and most complex designs.

Virtex FPGAs are SRAM-based, and are customized by loading configuration data into internal memory cells. In some modes, the FPGA reads its own configuration data from an external PROM (master serial mode). Otherwise, the configuration data is written into the FPGA (SelectMAP™, slave serial, and JTAG modes).

The standard Xilinx Foundation™ and Alliance Series™ Development systems deliver complete design support for Virtex, covering every aspect from behavioral and schematic entry, through simulation, automatic design translation and implementation, to the creation, downloading, and readback of a configuration bit stream.

## Higher Performance

Virtex devices provide better performance than previous generations of FPGA. Designs can achieve synchronous system clock rates up to 200 MHz including I/O. Virtex inputs and outputs comply fully with PCI specifications, and interfaces can be implemented that operate at 33 MHz or 66 MHz. Additionally, Virtex supports the hot-swapping requirements of Compact PCI.

Xilinx thoroughly benchmarked the Virtex family. While performance is design-dependent, many designs operated internally at speeds in excess of 100 MHz and can achieve 200 MHz. **Table 2** shows performance data for representative circuits, using worst-case timing parameters.

**Table 2: Performance for Common Circuit Functions**

Function	Bits	Virtex -6
Register-to-Register		
Adder	16	5.0 ns
	64	7.2 ns
Pipelined Multiplier	8 x 8	5.1 ns
	16 x 16	6.0 ns
Address Decoder	16	4.4 ns
	64	6.4 ns
16:1 Multiplexer		5.4 ns
Parity Tree	9	4.1 ns
	18	5.0 ns
	36	6.9 ns
Chip-to-Chip		
HSTL Class IV		200 MHz
LVTTL, 16mA, fast slew		180 MHz

### Input Path

A buffer in the Virtex IOB input path routes the input signal either directly to internal logic or through an optional input flip-flop.

An optional delay element at the D-input of this flip-flop eliminates pad-to-pad hold time. The delay is matched to the internal clock-distribution delay of the FPGA, and when used, assures that the pad-to-pad hold time is zero.

Each input buffer can be configured to conform to any of the low-voltage signalling standards supported. In some of these standards the input buffer utilizes a user-supplied threshold voltage,  $V_{REF}$ . The need to supply  $V_{REF}$  imposes constraints on which standards can be used in close proximity to each other. See [I/O Banking, page 3](#).

There are optional pull-up and pull-down resistors at each user I/O input for use after configuration. Their value is in the range 50 k $\Omega$  – 100 k $\Omega$ .

### Output Path

The output path includes a 3-state output buffer that drives the output signal onto the pad. The output signal can be routed to the buffer directly from the internal logic or through an optional IOB output flip-flop.

The 3-state control of the output can also be routed directly from the internal logic or through a flip-flop that provides synchronous enable and disable.

Each output driver can be individually programmed for a wide range of low-voltage signalling standards. Each output buffer can source up to 24 mA and sink up to 48mA. Drive strength and slew rate controls minimize bus transients.

In most signalling standards, the output High voltage depends on an externally supplied  $V_{CCO}$  voltage. The need to supply  $V_{CCO}$  imposes constraints on which standards can be used in close proximity to each other. See [I/O Banking, page 3](#).

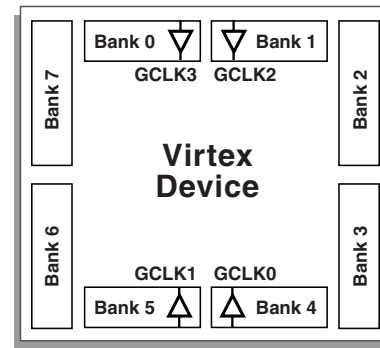
An optional weak-keeper circuit is connected to each output. When selected, the circuit monitors the voltage on the pad and weakly drives the pin High or Low to match the input signal. If the pin is connected to a multiple-source signal, the weak keeper holds the signal in its last state if all drivers are disabled. Maintaining a valid logic level in this way eliminates bus chatter.

Because the weak-keeper circuit uses the IOB input buffer to monitor the input level, an appropriate  $V_{REF}$  voltage must be provided if the signalling standard requires one. The provision of this voltage must comply with the I/O banking rules.

### I/O Banking

Some of the I/O standards described above require  $V_{CCO}$  and/or  $V_{REF}$  voltages. These voltages externally and connected to device pins that serve groups of IOBs, called banks. Consequently, restrictions exist about which I/O standards can be combined within a given bank.

Eight I/O banks result from separating each edge of the FPGA into two banks, as shown in [Figure 3](#). Each bank has multiple  $V_{CCO}$  pins, all of which must be connected to the same voltage. This voltage is determined by the output standards in use.



X8778\_b

Figure 3: Virtex I/O Banks

Within a bank, output standards can be mixed only if they use the same  $V_{CCO}$ . Compatible standards are shown in [Table 2](#). GTL and GTL+ appear under all voltages because their open-drain outputs do not depend on  $V_{CCO}$ .

Table 2: Compatible Output Standards

$V_{CCO}$	Compatible Standards
3.3 V	PCI, LVTTTL, SSTL3 I, SSTL3 II, CTT, AGP, GTL, GTL+
2.5 V	SSTL2 I, SSTL2 II, LVCMOS2, GTL, GTL+
1.5 V	HSTL I, HSTL III, HSTL IV, GTL, GTL+

Some input standards require a user-supplied threshold voltage,  $V_{REF}$ . In this case, certain user-I/O pins are automatically configured as inputs for the  $V_{REF}$  voltage. Approximately one in six of the I/O pins in the bank assume this role.

The  $V_{REF}$  pins within a bank are interconnected internally and consequently only one  $V_{REF}$  voltage can be used within each bank. All  $V_{REF}$  pins in the bank, however, must be connected to the external voltage source for correct operation.

Within a bank, inputs that require  $V_{REF}$  can be mixed with those that do not. However, only one  $V_{REF}$  voltage can be used within a bank. Input buffers that use  $V_{REF}$  are not 5 V tolerant. LVTTTL, LVCMOS2, and PCI 33 MHz 5 V, are 5 V tolerant.

The  $V_{CCO}$  and  $V_{REF}$  pins for each bank appear in the device Pinout tables and diagrams. The diagrams also show the bank affiliation of each I/O.

Within a given package, the number of  $V_{REF}$  and  $V_{CCO}$  pins can vary depending on the size of device. In larger devices,

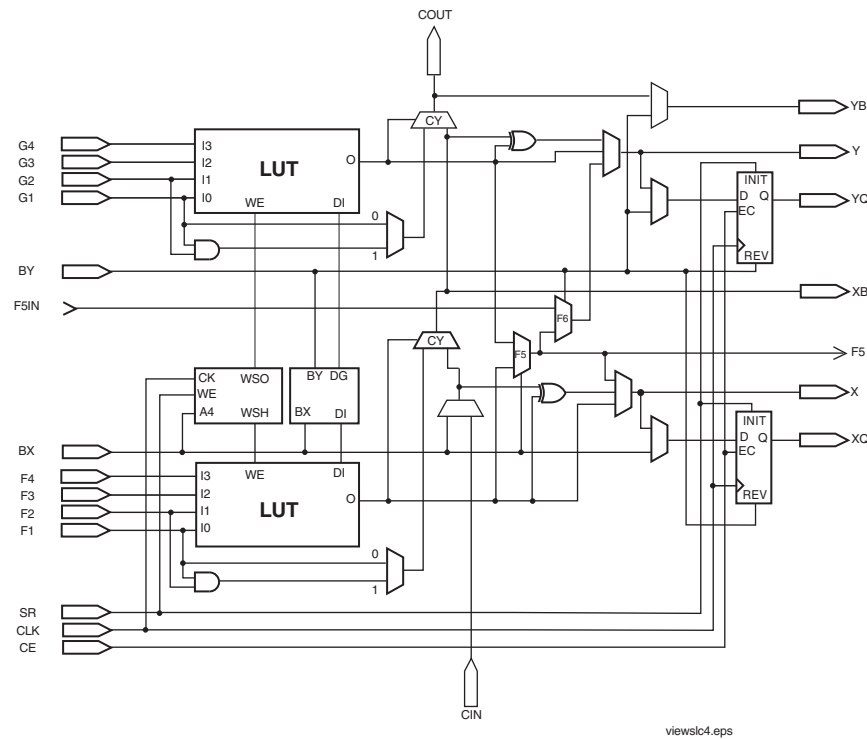


Figure 5: Detailed View of Virtex Slice

### Additional Logic

The F5 multiplexer in each slice combines the function generator outputs. This combination provides either a function generator that can implement any 5-input function, a 4:1 multiplexer, or selected functions of up to nine inputs.

Similarly, the F6 multiplexer combines the outputs of all four function generators in the CLB by selecting one of the F5-multiplexer outputs. This permits the implementation of any 6-input function, an 8:1 multiplexer, or selected functions of up to 19 inputs.

Each CLB has four direct feedthrough paths, one per LC. These paths provide extra data input or additional local routing that does not consume logic resources.

### Arithmetic Logic

Dedicated carry logic provides fast arithmetic carry capability for high-speed arithmetic functions. The Virtex CLB supports two separate carry chains, one per Slice. The height of the carry chains is two bits per CLB.

The arithmetic logic includes an XOR gate that allows a 1-bit full adder to be implemented within an LC. In addition, a dedicated AND gate improves the efficiency of multiplier implementation.

The dedicated carry path can also be used to cascade function generators for implementing wide logic functions.

### BUFTs

Each Virtex CLB contains two 3-state drivers (BUFTs) that can drive on-chip busses. See **Dedicated Routing**, page 7. Each Virtex BUFT has an independent 3-state control pin and an independent input pin.

### Block SelectRAM

Virtex FPGAs incorporate several large block SelectRAM memories. These complement the distributed LUT SelectRAMs that provide shallow RAM structures implemented in CLBs.

Block SelectRAM memory blocks are organized in columns. All Virtex devices contain two such columns, one along each vertical edge. These columns extend the full height of the chip. Each memory block is four CLBs high, and consequently, a Virtex device 64 CLBs high contains 16 memory blocks per column, and a total of 32 blocks.

Table 3 shows the amount of block SelectRAM memory that is available in each Virtex device.

Table 3: Virtex Block SelectRAM Amounts

Device	# of Blocks	Total Block SelectRAM Bits
XCV50	8	32,768
XCV100	10	40,960
XCV150	12	49,152
XCV200	14	57,344
XCV300	16	65,536
XCV400	20	81,920
XCV600	24	98,304
XCV800	28	114,688
XCV1000	32	131,072

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

**Figure 10** is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

### Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG\_IN, CFG\_OUT, and JSTART). The complete instruction set is coded as shown in **Table 5**.

### Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decoded of the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

### Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in **Figure 11**.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

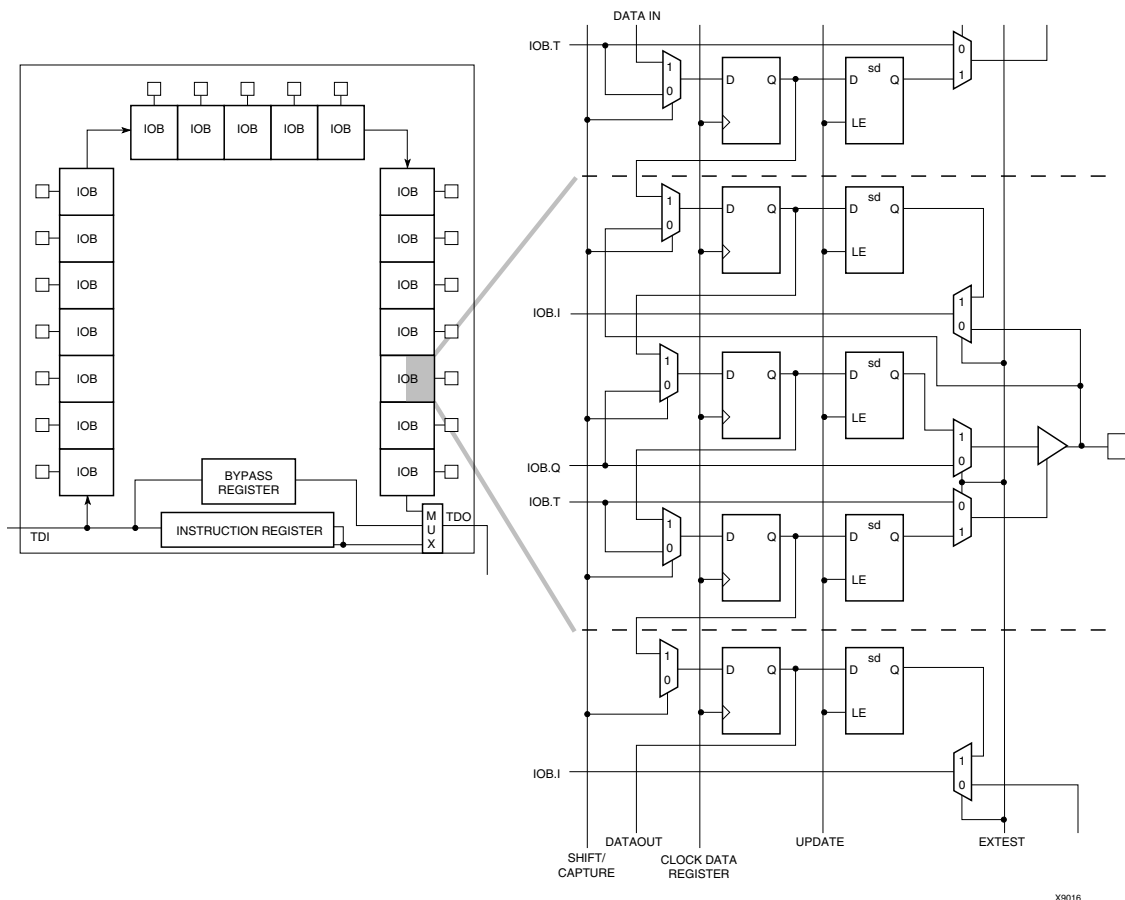


Figure 10: Virtex Series Boundary Scan Logic

## Configuration

Virtex devices are configured by loading configuration data into the internal configuration memory. Some of the pins used for this are dedicated configuration pins, while others can be re-used as general purpose inputs and outputs once configuration is complete.

The following are dedicated pins:

- Mode pins (M2, M1, M0)
- Configuration clock pin (CCLK)
- $\overline{\text{PROGRAM}}$  pin
- DONE pin
- Boundary-scan pins (TDI, TDO, TMS, TCK)

Depending on the configuration mode chosen, CCLK can be an output generated by the FPGA, or it can be generated externally and provided to the FPGA as an input. The  $\overline{\text{PROGRAM}}$  pin must be pulled High prior to reconfiguration.

Note that some configuration pins can act as outputs. For correct operation, these pins can require a  $V_{\text{CCO}}$  of 3.3 V to permit LVTTTL operation. All the pins affected are in banks 2 or 3. The configuration pins needed for SelectMap (CS, Write) are located in bank 1.

Table 7: Configuration Codes

Configuration Mode	M2	M1	M0	CCLK Direction	Data Width	Serial D <sub>out</sub>	Configuration Pull-ups
Master-serial mode	0	0	0	Out	1	Yes	No
Boundary-scan mode	1	0	1	N/A	1	No	No
SelectMAP mode	1	1	0	In	8	No	No
Slave-serial mode	1	1	1	In	1	Yes	No
Master-serial mode	1	0	0	Out	1	Yes	Yes
Boundary-scan mode	0	0	1	N/A	1	No	Yes
SelectMAP mode	0	1	0	In	8	No	Yes
Slave-serial mode	0	1	1	In	1	Yes	Yes

### Slave-Serial Mode

In slave-serial mode, the FPGA receives configuration data in bit-serial form from a serial PROM or other source of serial configuration data. The serial bitstream must be setup at the DIN input pin a short time before each rising edge of an externally generated CCLK.

For more information on serial PROMs, see the PROM data sheet at:

<http://www.xilinx.com/bvdocs/publications/ds026.pdf>.

Multiple FPGAs can be daisy-chained for configuration from a single source. After a particular FPGA has been configured, the data for the next device is routed to the DOUT pin. The data on the DOUT pin changes on the rising edge of CCLK.

The change of DOUT on the rising edge of CCLK differs from previous families, but does not cause a problem for

After Virtex devices are configured, unused IOBs function as 3-state OBUFTs with weak pull downs. For a more detailed description than that given below, see the XAPP138, Virtex Configuration and Readback.

## Configuration Modes

Virtex supports the following four configuration modes.

- Slave-serial mode
- Master-serial mode
- SelectMAP mode
- Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to configuration. The selection codes are listed in Table 7.

Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected. However, it is recommended to drive the configuration mode pins externally.

mixed configuration chains. This change was made to improve serial configuration rates for Virtex-only chains.

Figure 12 shows a full master/slave system. A Virtex device in slave-serial mode should be connected as shown in the third device from the left.

Slave-serial mode is selected by applying <111> or <011> to the mode pins (M2, M1, M0). A weak pull-up on the mode pins makes slave-serial the default mode if the pins are left unconnected. However, it is recommended to drive the configuration mode pins externally. Figure 13 shows slave-serial mode programming switching characteristics.

Table 8 provides more detail about the characteristics shown in Figure 13. Configuration must be delayed until the  $\overline{\text{INIT}}$  pins of all daisy-chained FPGAs are High.

### Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 “Virtex Configuration Architecture Advanced Users Guide”.

Table 11: Virtex Bit-Stream Lengths

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

### Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at [www.xilinx.com](http://www.xilinx.com).

### Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, “0” hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T <sub>IJITCC</sub> parameter, changed T <sub>OJIT</sub> to T <sub>OPHASE</sub> .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036, 111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V <sub>CCO</sub> in CS144 package on p.43.

### DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Device	Min	Max	Units
$V_{DRINT}$	Data Retention $V_{CCINT}$ Voltage (below which configuration data can be lost)	All	2.0		V
$V_{DRIO}$	Data Retention $V_{CCO}$ Voltage (below which configuration data can be lost)	All	1.2		V
$I_{CCINTQ}$	Quiescent $V_{CCINT}$ supply current <sup>(1,3)</sup>	XCV50		50	mA
		XCV100		50	mA
		XCV150		50	mA
		XCV200		75	mA
		XCV300		75	mA
		XCV400		75	mA
		XCV600		100	mA
		XCV800		100	mA
		XCV1000		100	mA
$I_{CCOQ}$	Quiescent $V_{CCO}$ supply current <sup>(1)</sup>	XCV50		2	mA
		XCV100		2	mA
		XCV150		2	mA
		XCV200		2	mA
		XCV300		2	mA
		XCV400		2	mA
		XCV600		2	mA
		XCV800		2	mA
		XCV1000		2	mA
$I_{REF}$	$V_{REF}$ current per $V_{REF}$ pin	All		20	$\mu$ A
$I_L$	Input or output leakage current	All	-10	+10	$\mu$ A
$C_{IN}$	Input capacitance (sample tested)	BGA, PQ, HQ, packages		8	pF
$I_{RPU}$	Pad pull-up (when selected) @ $V_{in} = 0$ V, $V_{CCO} = 3.3$ V (sample tested)	All	Note (2)	0.25	mA
$I_{RPD}$	Pad pull-down (when selected) @ $V_{in} = 3.6$ V (sample tested)		Note (2)	0.15	mA

#### Notes:

1. With no output current loads, no active input pull-up resistors, all I/O pins 3-stated and floating.
2. Internal pull-up and pull-down resistors guarantee valid logic levels at unconnected input pins. These pull-up and pull-down resistors do not guarantee valid logic levels when input pins are connected to other circuits.
3. Multiply  $I_{CCINTQ}$  limit by two for industrial grade.

### IOB Input Switching Characteristics Standard Adjustments

Description	Symbol	Standard <sup>(1)</sup>	Speed Grade				Units
			Min	-6	-5	-4	
Data Input Delay Adjustments							
Standard-specific data input delay adjustments	T <sub>ILVTTL</sub>	LVTTL	0	0	0	0	ns
	T <sub>ILVCMOS2</sub>	LVCMSO2	−0.02	−0.04	−0.04	−0.05	ns
	T <sub>IPCI33_3</sub>	PCI, 33 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns
	T <sub>IPCI33_5</sub>	PCI, 33 MHz, 5.0 V	0.13	0.25	0.28	0.33	ns
	T <sub>IPCI66_3</sub>	PCI, 66 MHz, 3.3 V	−0.05	−0.11	−0.12	−0.14	ns
	T <sub>IGTL</sub>	GTL	0.10	0.20	0.23	0.26	ns
	T <sub>IGTLP</sub>	GTL+	0.06	0.11	0.12	0.14	ns
	T <sub>IHSTL</sub>	HSTL	0.02	0.03	0.03	0.04	ns
	T <sub>ISSTL2</sub>	SSTL2	−0.04	−0.08	−0.09	−0.10	ns
	T <sub>ISSTL3</sub>	SSTL3	−0.02	−0.04	−0.05	−0.06	ns
	T <sub>ICTT</sub>	CTT	0.01	0.02	0.02	0.02	ns
	T <sub>IAGP</sub>	AGP	−0.03	−0.06	−0.07	−0.08	ns

#### Notes:

- Input timing for LVTTL is measured at 1.4 V. For other I/O standards, see [Table 3](#).

### IOB Output Switching Characteristics

Output delays terminating at a pad are specified for LVTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays with the values shown in [IOB Output Switching Characteristics Standard Adjustments, page 9](#).

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Propagation Delays						
O input to Pad	T <sub>IOOP</sub>	1.2	2.9	3.2	3.5	ns, max
O input to Pad via transparent latch	T <sub>IOOLP</sub>	1.4	3.4	3.7	4.0	ns, max
3-State Delays						
T input to Pad high-impedance <sup>(1)</sup>	T <sub>IOTHZ</sub>	1.0	2.0	2.2	2.4	ns, max
T input to valid data on Pad	T <sub>IOTON</sub>	1.4	3.1	3.3	3.7	ns, max
T input to Pad high-impedance via transparent latch <sup>(1)</sup>	T <sub>IOTLPHZ</sub>	1.2	2.4	2.6	3.0	ns, max
T input to valid data on Pad via transparent latch	T <sub>IOTLPON</sub>	1.6	3.5	3.8	4.2	ns, max
GTS to Pad high impedance <sup>(1)</sup>	T <sub>GTS</sub>	2.5	4.9	5.5	6.3	ns, max
Sequential Delays						
Clock CLK						
Minimum Pulse Width, High	T <sub>CH</sub>	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T <sub>CL</sub>	0.8	1.5	1.7	2.0	ns, min

Description	Symbol	Speed Grade				Units
		Min	-6	-5	-4	
Clock CLK to Pad delay with OBUFT enabled (non-3-state)	$T_{IOCKP}$	1.0	2.9	3.2	3.5	ns, max
Clock CLK to Pad high-impedance (synchronous) <sup>(1)</sup>	$T_{IOCKHZ}$	1.1	2.3	2.5	2.9	ns, max
Clock CLK to valid data on Pad delay, plus enable delay for OBUFT	$T_{IOCKON}$	1.5	3.4	3.7	4.1	ns, max
<b>Setup and Hold Times before/after Clock CLK<sup>(2)</sup></b>		<b>Setup Time / Hold Time</b>				
O input	$T_{IOOCK}/T_{IOCKO}$	0.51 / 0	1.1 / 0	1.2 / 0	1.3 / 0	ns, min
OCE input	$T_{IOOCECK}/T_{IOCKOCE}$	0.37 / 0	0.8 / 0	0.9 / 0	1.0 / 0	ns, min
SR input (OFF)	$T_{IOSRCKO}/T_{IOCKOSR}$	0.52 / 0	1.1 / 0	1.2 / 0	1.4 / 0	ns, min
3-State Setup Times, T input	$T_{IOTCK}/T_{IOCKT}$	0.34 / 0	0.7 / 0	0.8 / 0	0.9 / 0	ns, min
3-State Setup Times, TCE input	$T_{IOTCECK}/T_{IOCKTCE}$	0.41 / 0	0.9 / 0	0.9 / 0	1.1 / 0	ns, min
3-State Setup Times, SR input (TFF)	$T_{IOSRCKT}/T_{IOCKTSR}$	0.49 / 0	1.0 / 0	1.1 / 0	1.3 / 0	ns, min
<b>Set/Reset Delays</b>						
SR input to Pad (asynchronous)	$T_{IOSRP}$	1.6	3.8	4.1	4.6	ns, max
SR input to Pad high-impedance (asynchronous) <sup>(1)</sup>	$T_{IOSRHZ}$	1.6	3.1	3.4	3.9	ns, max
SR input to valid data on Pad (asynchronous)	$T_{IOSRON}$	2.0	4.2	4.6	5.1	ns, max
GSR to Pad	$T_{IOGSRQ}$	4.9	9.7	10.9	12.5	ns, max

**Notes:**

1. 3-state turn-off delays should not be adjusted.
2. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

### IOB Output Switching Characteristics Standard Adjustments

Output delays terminating at a pad are specified for LVTTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays by the values shown.

Description	Symbol	Standard <sup>(1)</sup>	Speed Grade				Unit s
			Min	-6	-5	-4	
Output Delay Adjustments							
Standard-specific adjustments for output delays terminating at pads (based on standard capacitive load, Csl)	T <sub>OLVTTL_S2</sub>	LVTTL, Slow, 2 mA	4.2	14.7	15.8	17.0	ns
	T <sub>OLVTTL_S4</sub>	4 mA	2.5	7.5	8.0	8.6	ns
	T <sub>OLVTTL_S6</sub>	6 mA	1.8	4.8	5.1	5.6	ns
	T <sub>OLVTTL_S8</sub>	8 mA	1.2	3.0	3.3	3.5	ns
	T <sub>OLVTTL_S12</sub>	12 mA	1.0	1.9	2.1	2.2	ns
	T <sub>OLVTTL_S16</sub>	16 mA	0.9	1.7	1.9	2.0	ns
	T <sub>OLVTTL_S24</sub>	24 mA	0.8	1.3	1.4	1.6	ns
	T <sub>OLVTTL_F2</sub>	LVTTL, Fast, 2mA	1.9	13.1	14.0	15.1	ns
	T <sub>OLVTTL_F4</sub>	4 mA	0.7	5.3	5.7	6.1	ns
	T <sub>OLVTTL_F6</sub>	6 mA	0.2	3.1	3.3	3.6	ns
	T <sub>OLVTTL_F8</sub>	8 mA	0.1	1.0	1.1	1.2	ns
	T <sub>OLVTTL_F12</sub>	12 mA	0	0	0	0	ns
	T <sub>OLVTTL_F16</sub>	16 mA	−0.10	−0.05	−0.05	−0.05	ns
	T <sub>OLVTTL_F24</sub>	24 mA	−0.10	−0.20	−0.21	−0.23	ns
	T <sub>OLVCMOS2</sub>	LVC MOS2	0.10	0.10	0.11	0.12	ns
	T <sub>OPCI33_3</sub>	PCI, 33 MHz, 3.3 V	0.50	2.3	2.5	2.7	ns
	T <sub>OPCI33_5</sub>	PCI, 33 MHz, 5.0 V	0.40	2.8	3.0	3.3	ns
	T <sub>OPCI66_3</sub>	PCI, 66 MHz, 3.3 V	0.10	−0.40	−0.42	−0.46	ns
	T <sub>OGTL</sub>	GTL	0.6	0.50	0.54	0.6	ns
	T <sub>OGTLP</sub>	GTL+	0.7	0.8	0.9	1.0	ns
	T <sub>OHSTL_I</sub>	HSTL I	0.10	−0.50	−0.53	−0.5	ns
	T <sub>OHSTL_III</sub>	HSTL III	−0.10	−0.9	−0.9	−1.0	ns
	T <sub>OHSTL_IV</sub>	HSTL IV	−0.20	−1.0	−1.0	−1.1	ns
	T <sub>OSSTL2_I</sub>	SSTL2 I	−0.10	−0.50	−0.53	−0.5	ns
	T <sub>OSSTL2_II</sub>	SSTL2 II	−0.20	−0.9	−0.9	−1.0	ns
	T <sub>OSSTL3_I</sub>	SSTL3 I	−0.20	−0.50	−0.53	−0.5	ns
	T <sub>OSSTL3_II</sub>	SSTL3 II	−0.30	−1.0	−1.0	−1.1	ns
	T <sub>OCTT</sub>	CTT	0	−0.6	−0.6	−0.6	ns
	T <sub>OAGP</sub>	AGP	0	−0.9	−0.9	−1.0	ns

#### Notes:

- Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTTL. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).

### Virtex Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Listed below are representative values for typical pin locations and normal clock loading. Values are expressed in nanoseconds unless otherwise noted.

#### Global Clock Input to Output Delay for LVTTL, 12 mA, Fast Slew Rate, *with* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>with</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Output Delay Adjustments.	T <sub>ICKOFDLL</sub>	XCV50	1.0	3.1	3.3	3.6	ns, max
		XCV100	1.0	3.1	3.3	3.6	ns, max
		XCV150	1.0	3.1	3.3	3.6	ns, max
		XCV200	1.0	3.1	3.3	3.6	ns, max
		XCV300	1.0	3.1	3.3	3.6	ns, max
		XCV400	1.0	3.1	3.3	3.6	ns, max
		XCV600	1.0	3.1	3.3	3.6	ns, max
		XCV800	1.0	3.1	3.3	3.6	ns, max
		XCV1000	1.0	3.1	3.3	3.6	ns, max

#### Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).
3. DLL output jitter is already included in the timing calculation.

#### Global Clock Input-to-Output Delay for LVTTL, 12 mA, Fast Slew Rate, *without* DLL

Description	Symbol	Device	Speed Grade				Units
			Min	-6	-5	-4	
LVTTL Global Clock Input to Output Delay using Output Flip-flop, 12 mA, Fast Slew Rate, <i>without</i> DLL. For data <i>output</i> with different standards, adjust delays with the values shown in Input and Output Delay Adjustments. For I/O standards requiring V <sub>REF</sub> such as GTL, GTL+, SSTL, HSTL, CTT, and AGO, an additional 600 ps must be added.	T <sub>ICKOF</sub>	XCV50	1.5	4.6	5.1	5.7	ns, max
		XCV100	1.5	4.6	5.1	5.7	ns, max
		XCV150	1.5	4.7	5.2	5.8	ns, max
		XCV200	1.5	4.7	5.2	5.8	ns, max
		XCV300	1.5	4.7	5.2	5.9	ns, max
		XCV400	1.5	4.8	5.3	6.0	ns, max
		XCV600	1.6	4.9	5.4	6.0	ns, max
		XCV800	1.6	4.9	5.5	6.2	ns, max
		XCV1000	1.7	5.0	5.6	6.3	ns, max

#### Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4 V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see [Table 2](#) and [Table 3](#).

*Table 3: Virtex Pinout Tables (BGA)*

Pin Name	Device	BG256	BG352	BG432	BG560
GCK0	All	Y11	AE13	AL16	AL17
GCK1	All	Y10	AF14	AK16	AJ17
GCK2	All	A10	B14	A16	D17
GCK3	All	B10	D14	D17	A17
M0	All	Y1	AD24	AH28	AJ29
M1	All	U3	AB23	AH29	AK30
M2	All	W2	AC23	AJ28	AN32
CCLK	All	B19	C3	D4	C4
PROGRAM	All	Y20	AC4	AH3	AM1
DONE	All	W19	AD3	AH4	AJ5
INIT	All	U18	AD2	AJ2	AH5
BUSY/DOUT	All	D18	E4	D3	D4
D0/DIN	All	C19	D3	C2	E4
D1	All	E20	G1	K4	K3
D2	All	G19	J3	K2	L4
D3	All	J19	M3	P4	P3
D4	All	M19	R3	V4	W4
D5	All	P19	U4	AB1	AB5
D6	All	T20	V3	AB3	AC4
D7	All	V19	AC3	AG4	AJ4
WRITE	All	A19	D5	B4	D6
CS	All	B18	C4	D5	A2
TDI	All	C17	B3	B3	D5
TDO	All	A20	D4	C4	E6
TMS	All	D3	D23	D29	B33
TCK	All	A1	C24	D28	E29
DXN	All	W3	AD23	AH27	AK29
DXP	All	V4	AE24	AK29	AJ28

Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
V <sub>CCINT</sub>	All	C3, C14, D4, D13, E5, E12, M5, M12, N4, N13, P3, P14	E5, E18, F6, F17, G7, G8, G9, G14, G15, G16, H7, H16, J7, J16, P7, P16, R7, R16, T7, T8, T9, T14, T15, T16, U6, U17, V5, V18	G7, G20, H8, H19, J9, J10, J11, J16, J17, J18, K9, K18, L9, L18, T9, T18, U9, U18, V9, V10, V11, V16, V17, V18, W8, W19, Y7, Y20	AD5, AD35, AE5, AE35, AL5, AL35, AM5, AM35, AR8, AR9, AR15, AR16, AR24, AR25, AR31, AR32, E8, E9, E15, E16, E24, E25, E31, E32, H5, H35, J5, J35, R5, R35, T5, T35
V <sub>CCO</sub> , Bank 0	All	E8, F8	F7, F8, F9, F10, G10, G11	H9, H10, H11, H12, J12, J13	E26, E27, E29, E30, E33, E34
V <sub>CCO</sub> , Bank 1	All	E9, F9	F13, F14, F15, F16, G12, G13	H15, H16, H17, H18, J14, J15	E6, E7, E10, E11, E13, E14
V <sub>CCO</sub> , Bank 2	All	H11, H12	G17, H17, J17, K16, K17, L16	J19, K19, L19, M18, M19, N18	F5, G5, K5, L5, N5, P5
V <sub>CCO</sub> , Bank 3	All	J11, J12	M16, N16, N17, P17, R17, T17	P18, R18, R19, T19, U19, V19	AF5, AG5, AN5, AK5, AJ5, AP5
V <sub>CCO</sub> , Bank 4	All	L9, M9	T12, T13, U13, U14, U15, U16,	V14, V15, W15, W16, W17, W18	AR6, AR7, AR10, AR11, AR13, AR14
V <sub>CCO</sub> , Bank 5	All	L8, M8	T10, T11, U7, U8, U9, U10	V12, V13, W9, W10, W11, W12	AR26, AR27, AR29, AR30, AR33, AR34
V <sub>CCO</sub> , Bank 6	All	J5, J6	M7, N6, N7, P6, R6, T6	P9, R8, R9, T8, U8, V8	AF35, AG35, AJ35, AK35, AN35, AP35
V <sub>CCO</sub> , Bank 7	All	H5, H6	G6, H6, J6, K6, K7, L7	J8, K8, L8, M8, M9, N9	F35, G35, K35, L35, N35, P35
V <sub>REF</sub> , Bank 0 (VREF pins are listed incrementally. Connect all pins listed for both the required device and all smaller devices listed in the same package.) Within each bank, if input reference voltage is not required, all V <sub>REF</sub> pins are general I/O.	XCV50	B4, B7	N/A	N/A	N/A
	XCV100/150	... + C6	A9, C6, E8	N/A	N/A
	XCV200/300	... + A3	... + B4	N/A	N/A
	XCV400	N/A	N/A	A12, C11, D6, E8, G10	
	XCV600	N/A	N/A	... + B7	A33, B28, B30, C23, C24, D33
	XCV800	N/A	N/A	... + B10	... + A26
	XCV1000	N/A	N/A	N/A	... + D34

Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
No Connect (No-connect pins are listed incrementally. All pins listed for both the required device and all larger devices listed in the same package are no connects.)	XCV800	N/A	N/A	A2, A3, A15, A25, B1, B6, B11, B16, B21, B24, B26, C1, C2, C25, C26, F2, F6, F21, F25, L2, L25, N25, P2, T2, T25, AA2, AA6, AA21, AA25, AD1, AD2, AD25, AE1, AE3, AE6, AE11, AE14, AE16, AE21, AE24, AE26, AF2, AF24, AF25	N/A
	XCV600	N/A	N/A	same as above	N/A
	XCV400	N/A	N/A	... + A9, A10, A13, A16, A24, AC1, AC25, AE12, AE15, AF3, AF10, AF11, AF13, AF14, AF16, AF18, AF23, B4, B12, B13, B15, B17, D1, D25, H26, J1, K26, L1, M1, M25, N1, N26, P1, P26, R2, R26, T1, T26, U26, V1	N/A
	XCV300	N/A	D4, D19, W4, W19	N/A	N/A
	XCV200	N/A	... + A2, A6, A12, B11, B16, C2, D1, D18, E17, E19, G2, G22, L2, L19, M2, M21, R3, R20, U3, U18, Y22, AA1, AA3, AA11, AA16, AB7, AB12, AB21,	N/A	N/A
	XCV150	N/A	... + A13, A14, C8, C9, E13, F11, H21, J1, J4, K2, K18, K19, M17, N1, P1, P5, P22, R22, W13, W15, AA9, AA10, AB8, AB14	N/A	N/A

## Pinout Diagrams

The following diagrams, **CS144 Pin Function Diagram**, page 17 through **FG680 Pin Function Diagram**, page 27, illustrate the locations of special-purpose pins on Virtex FPGAs. Table 5 lists the symbols used in these diagrams. The diagrams also show I/O-bank boundaries.

Table 5: Pinout Diagram Symbols

Symbol	Pin Function
*	General I/O
*	Device-dependent general I/O, n/c on smaller devices
V	V <sub>CCINT</sub>
v	Device-dependent V <sub>CCINT</sub> , n/c on smaller devices
O	V <sub>CCO</sub>
R	V <sub>REF</sub>
r	Device-dependent V <sub>REF</sub> , remains I/O on smaller devices
G	Ground
Ø, 1, 2, 3	Global Clocks

Table 5: Pinout Diagram Symbols (Continued)

Symbol	Pin Function
⑩, ①, ②	M0, M1, M2
⑩, ①, ②, ③, ④, ⑤, ⑥, ⑦	D0/DIN, D1, D2, D3, D4, D5, D6, D7
B	DOUT/BUSY
D	DONE
P	PROGRAM
I	INIT
K	CCLK
W	WRITE
S	CS
T	Boundary-scan Test Access Port
+	Temperature diode, anode
–	Temperature diode, cathode
n	No connect

## CS144 Pin Function Diagram

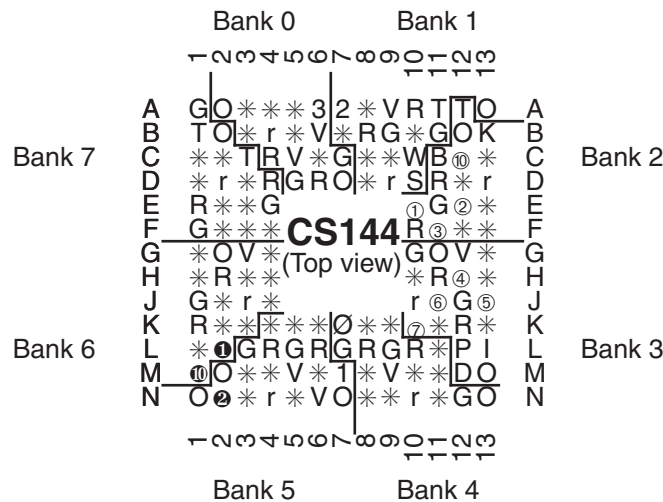


Figure 1: CS144 Pin Function Diagram

## PQ240/HQ240 Pin Function Diagram

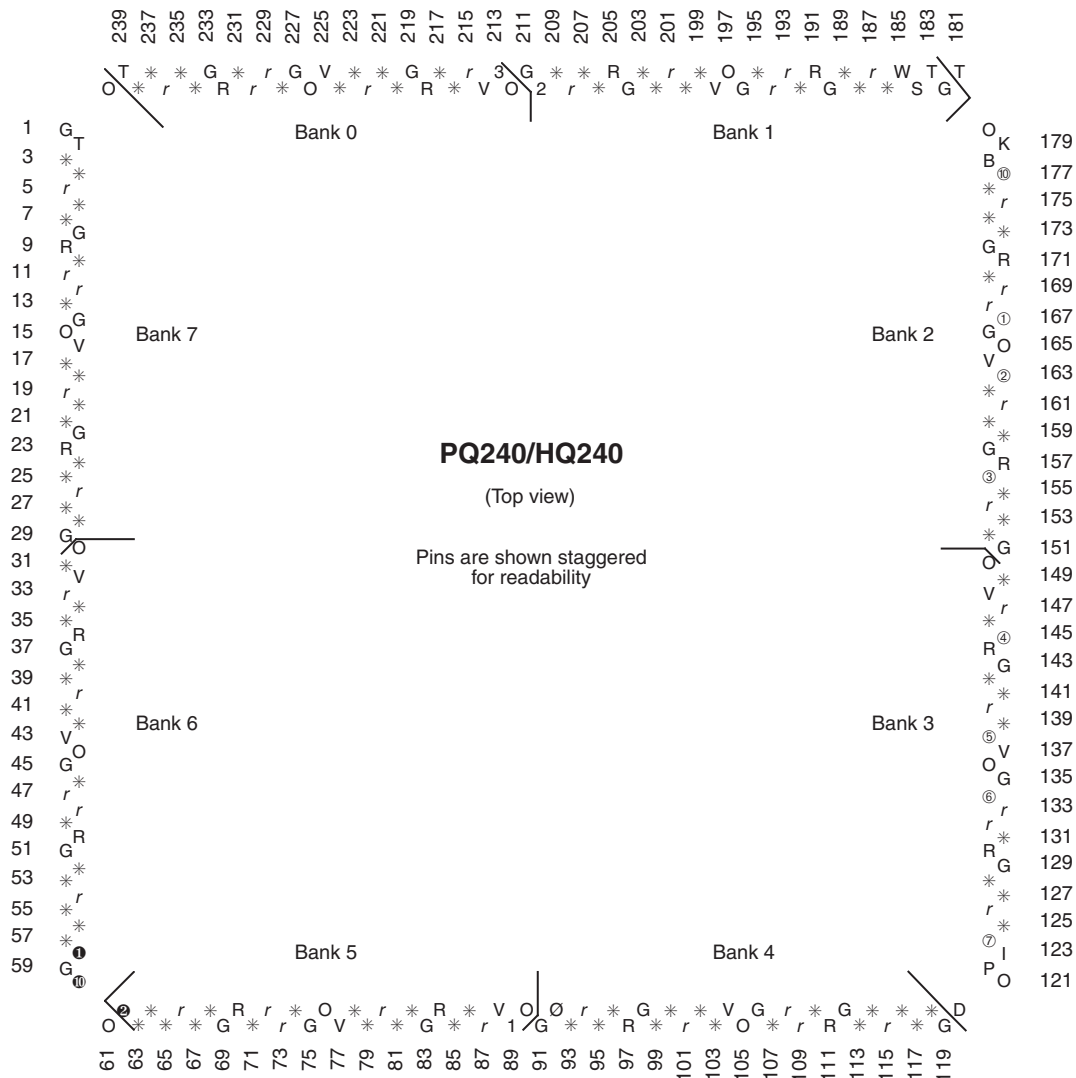
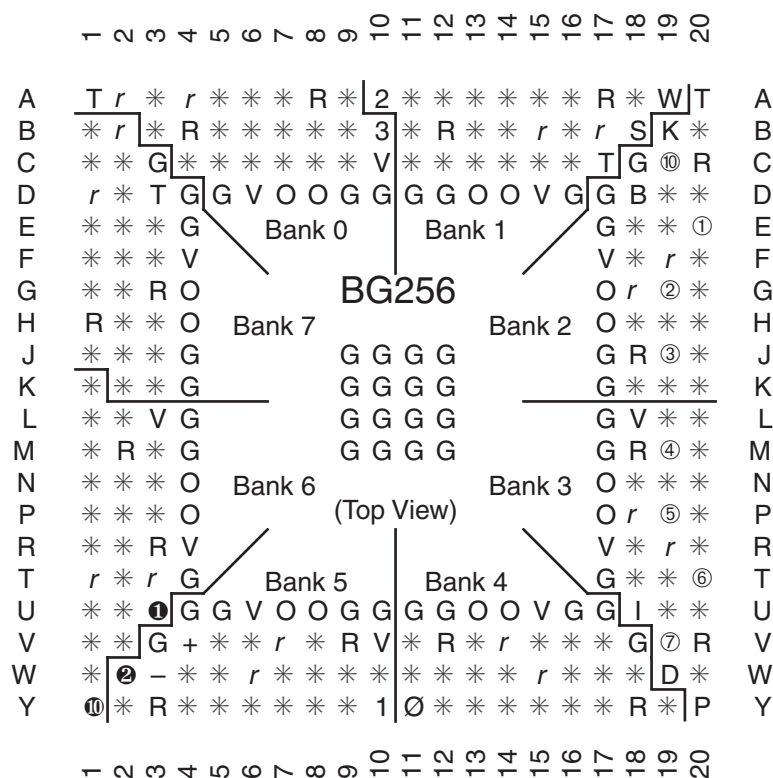


Figure 3: PQ240/HQ240 Pin Function Diagram

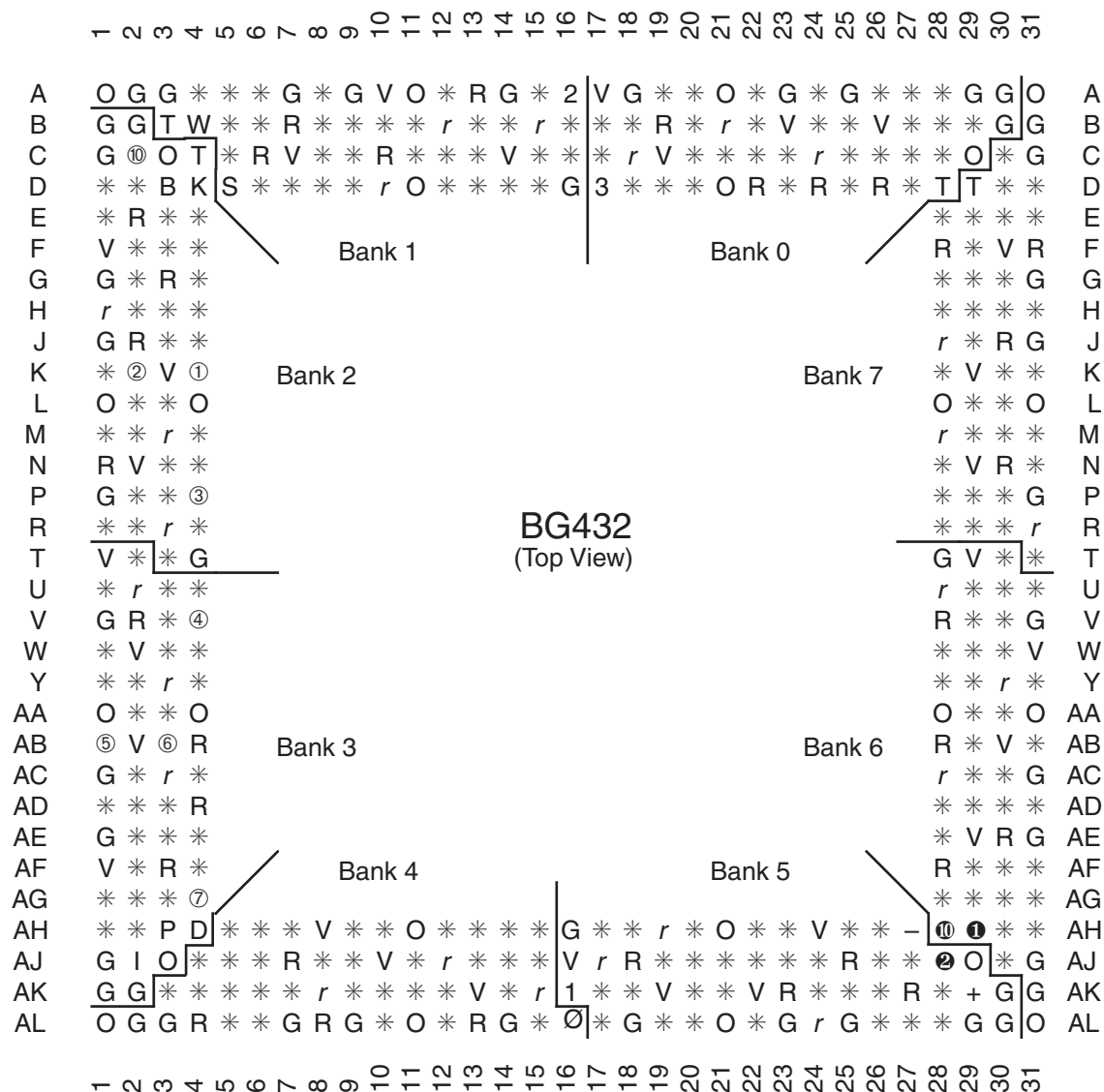
## BG256 Pin Function Diagram



DS003 18 100300

**Figure 4: BG256 Pin Function Diagram**

## BG432 Pin Function Diagram

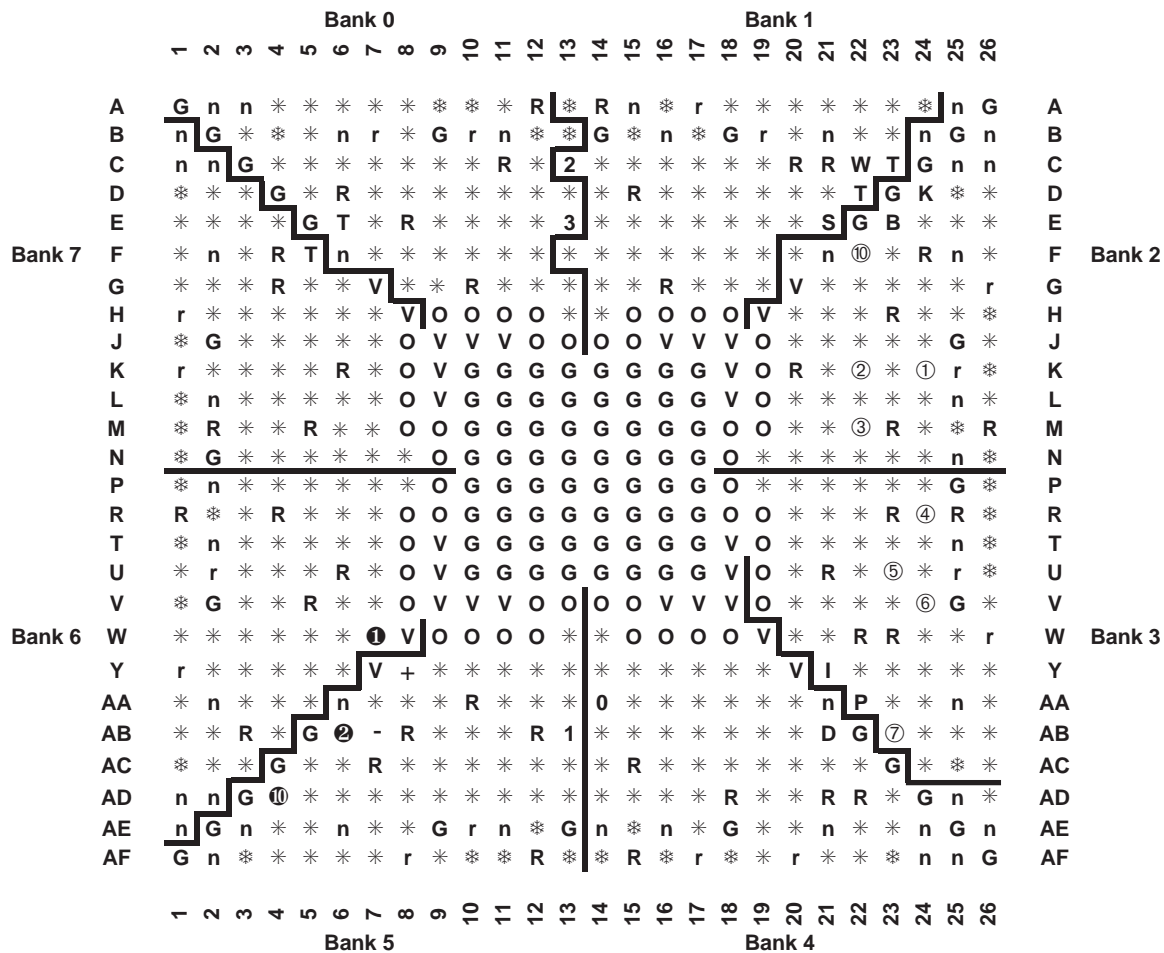


DS003\_21\_100300

**Figure 6: BG432 Pin Function Diagram**



## FG676 Pin Function Diagram



**Figure 10: FG676 Pin Function Diagram**

**Notes:**

Packages FG456 and FG676 are layout compatible.